- High-Speed, Low-Skew 1-to-10 Clock Buffer for SDRAM (Synchronous DRAM) Clock Buffering Applications
- Output Skew, t<sub>sk(o)</sub>, Less Than 250 ps
- Pulse Skew, t<sub>sk(p)</sub>, Less Than 500 ps
- Supports up to Two Unbuffered SDRAM DIMMs (Dual Inline Memory Modules)
- I<sup>2</sup>C Serial Interface Provides Individual Enable Control for Each Output
- Operates at 3.3 V
- Distributed V<sub>CC</sub> and Ground Pins Reduce Switching Noise
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015
- Packaged in 28-Pin Shrink Small Outline (DB) Package

#### description

The CDC319 is a high-performance clock buffer that distributes one input (A) to 10 outputs (Y) with minimum skew for clock distribution. The CDC319 operates from a 3.3-V power supply, and is characterized for operation from 0°C to 70°C.

The device provides a standard mode (100K-bits/s) I<sup>2</sup>C serial interface for device control. The implementation is as a slave/receiver. The device address is specified in the I<sup>2</sup>C device address table. Both of the I<sup>2</sup>C inputs (SDATA and SCLOCK) provide integrated pullup resistors (typically 140 k $\Omega$ ) and are 5-V tolerant.

Three 8-bit I<sup>2</sup>C registers provide individual enable control for each of the outputs. All outputs default to enabled at powerup. Each output can be placed in a disabled mode with a low-level output when a low-level control bit is written to the control register. The registers are write only and must be accessed in sequential order (i.e., random access of the registers is not supported).

The CDC319 provides 3-state outputs for testing and debugging purposes. The outputs can be placed in a high-impedance state via the output-enable (OE) input. When OE is high, all outputs are in the operational state. When OE is low, the outputs are placed in a high-impedance state. OE provides an integrated pullup resistor.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



(TOP VIEW) 10 28 V<sub>CC</sub>  $\square$ Vcc 2 27 1Y0 🗖 2Y3 1Y1 🗖 3 26 2Y2 4 25 GND GND E 5 24 Vcc V<sub>CC</sub> ⊏ 1Y2 🗆 6 23 1 2Y1 7 22 1Y3 🗖 1 2Y0 8 21 GND 🗖 🗖 GND 9  $A \square$ 20 19 10 V<sub>CC</sub>  $\square$ 3Y0 🗖 11 18 **\_\_\_** 3Y1 GND 🗖 12 17 V<sub>CC</sub> L 13 16 SDATA C 14 15 SCLOCK

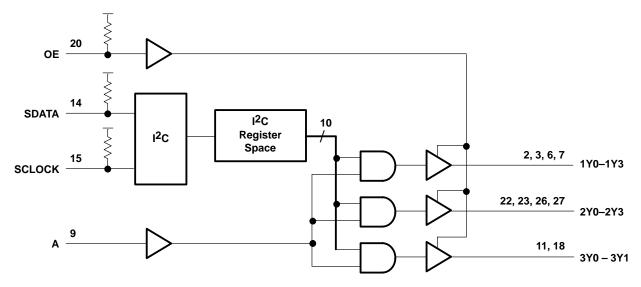
DB PACKAGE

#### FUNCTION TABLE

INP	JTS	OUTPUTS					
OE	Α	1Y0–1Y3	2Y0–2Y3	3Y0–3Y1			
L	Х	Hi-Z	Hi-Z	Hi-Z			
Н	L	L	L	L			
н	Н	н†	H <sup>†</sup>	нţ			

<sup>†</sup>The function table assumes that all outputs are enabled via the appropriate I<sup>2</sup>C configuration register bit. If the output is disabled via the appropriate configuration bit, then the output is driven to a low state, regardless of the state of the A input.

## logic diagram (positive logic)



## **Terminal Functions**

Т	TERMINAL		DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
1Y0–1Y3	2, 3, 6, 7	0	3.3-V SDRAM byte 0 clock outputs
2Y0–2Y3	22, 23, 26, 27	0	3.3-V SDRAM byte 1 clock outputs
3Y0–3Y1	11, 18	0	3.3-V clock outputs provided for feedback control of external PLLs (phase-locked loops)
А	9	I	Clock input
OE	20	I	Output enable. When asserted, OE puts all outputs in a high-impedance state. A nominal 140-k $\Omega$ pullup resistor is internally integrated.
SCLOCK	15	I	l <sup>2</sup> C serial clock input. A nominal 140-k $\Omega$ pullup resistor is internally integrated.
SDATA	14	I/O	Bidirectional I <sup>2</sup> C serial data input/output. A nominal 140-k $\Omega$ pullup resistor is internally integrated.
GND	4, 8, 12, 16, 17, 21, 25		Ground
Vcc	1, 5, 10, 13, 19, 24, 28		3.3-V power supply



#### I<sup>2</sup>C DEVICE ADDRESS

A7	A6	A5	A4	A3	A2	A1	A0 (R/W)
Н	Н	L	Н	L	L	Н	-

BIT	DEFINITION	DEFAULT VALUE
7	Reserved	Н
6	Reserved	Н
5	Reserved	Н
4	Reserved	Н
3	1Y3 enable (pin 7)	Н
2	1Y2 enable (pin 6)	Н
1	1Y1 enable (pin 3)	Н
0	1Y0 enable (pin 2)	Н

#### I<sup>2</sup>C BYTE 0-BIT DEFINITION<sup>†</sup>

<sup>†</sup> When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.

BIT	DEFINITION	DEFAULT VALUE
7	2Y3 enable (pin 27)	Н
6	2Y2 enable (pin 26)	Н
5	2Y1 enable (pin 23)	Н
4	2Y0 enable (pin 22)	Н
3	Reserved	Н
2	Reserved	Н
1	Reserved	Н
0	Reserved	Н

#### I<sup>2</sup>C BYTE 1-BIT DEFINITION<sup>†</sup>

<sup>†</sup> When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.

BIT	DEFINITION	DEFAULT VALUE
7	3Y1 enable (pin 18)	Н
6	3Y0 enable (pin 11)	Н
5	Reserved	Н
4	Reserved	Н
3	Reserved	Н
2	Reserved	Н
1	Reserved	Н
0	Reserved	Н

#### I<sup>2</sup>C BYTE 2-BIT DEFINITION<sup>†</sup>

<sup>†</sup> When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.



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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, $V_{CC}$ Input voltage range, $V_I$ (see Note 1) Input voltage range, $V_I$ (SCLOCK, SDATA) (see Note 1) Output voltage range, $V_O$ (SDATA) (see Note 1) Voltage range applied to any output in the high-impedance or power-off state, $V_O$ 0.5 Current into any output in the low state (except SDATA), $I_O$ Current into SDATA in the low state, $I_O$ Input clamp current, $I_{IK}$ ( $V_I < 0$ ) (SCLOCK) Output clamp current, $I_{OK}$ ( $V_O < 0$ ) (SDATA) Package thermal impedance, $\theta_{JA}$ (see Note 2) Storage temperature range, $T_{sto}$	$\begin{array}{c} -0.5 \ V \ to \ 4.6 \ V \\ -0.5 \ V \ to \ 6.5 \ V \\ -0.5 \ V \ to \ 6.5 \ V \\ 5 \ V \ to \ V_{CC} \ + \ 0.5 \ V \\ -0.5 \ V \ to \ V_{CC} \ + \ 0.5 \ V \ to \ V_{CC} \ + \ 0.5 \ V \\ -0.5 \ V \ to \ V_{CC} \ + \ V_{CC} \ + \ 0.5 \ V \ to \ V_{CC} \ + \ 0.5 \ V \ to \ V \ to \ V \ to \ V_{CC} \ + \ 0.5 \ V \ to \ v \ v \ v \ v \ v \ v \ v \ v \ v \ $
Storage temperature range, T <sub>stg</sub>	. –65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.

			MIN	TYP MA	х иліт
VCC	3.3-V core supply voltage	3.135	3.46	5 V	
		A, OE	2	V <sub>CC</sub> +0.	3 V
VIH	High-level input voltage	SDATA, SCLOCK (see Note 3)	2.2	5.	5 V
		A, OE	-0.3	0.	8 V
VIL	Low-level input voltage	SDATA, SCLOCK (see Note 3)	0	1.0	4 V
ЮН	High-level output current	Y outputs		-2	4 mA
IOL	Low-level output current	Y outputs		2	4 mA
RJ	Input resistance to V <sub>CC</sub>	SDATA, SCLOCK (see Note 3)		140	kΩ
f(SCL)	SCLOCK frequency			10	0 kHz
<sup>t</sup> (BUS)	Bus free time		4.7		μs
<sup>t</sup> su(START)	START setup time		4.7		μs
<sup>t</sup> h(START)	START hold time		4		μs
<sup>t</sup> w(SCLL)	SCLOCK low pulse duration		4.7		μs
<sup>t</sup> w(SCLH)	SCLOCK high pulse duration		4		μs
<sup>t</sup> r(SDATA)	SDATA input rise time			100	0 ns
<sup>t</sup> f(SDATA)	SDATA input fall time			30	0 ns
<sup>t</sup> su(SDATA)	SDATA setup time		250		ns
<sup>t</sup> h(SDATA)	SDATA hold time		0		ns
<sup>t</sup> su(STOP)	STOP setup time		4		μs
Тд	Operating free-air temperature		0	7	0°C

#### recommended operating conditions (see Note 3)

NOTE 3: The CMOS-level inputs fall within these limits:  $V_{IH}$  min = 0.7 ×  $V_{CC}$  and  $V_{IL}$  max = 0.3 ×  $V_{CC}$ .



# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CON	TEST CONDITIONS			MAX	UNIT	
VIK	Input clamp voltage		V <sub>CC</sub> = 3.135 V,	l <sub>l</sub> = –18 mA			-1.2	V	
Vон	High-level output voltage	Y outputs	V <sub>CC</sub> = 3.135 V,	I <sub>OH</sub> = –1 mA	2.4			V	
		Y outputs	V <sub>CC</sub> = 3.135 V,	I <sub>OL</sub> = 1 mA			0.4		
VOL	Low-level output voltage	SDATA	V <sub>CC</sub> = 3.135 V	I <sub>OL</sub> = 3 mA	0.1		0.4	V	
		SDATA	VCC = 3.135 V	I <sub>OL</sub> = 6 mA	0.2		0.6		
		SDATA	V <sub>CC</sub> = 3.135 V,	VO = NCC WAX			20	μA	
10.1	High lovel output ourrent		V <sub>CC</sub> = 3.135 V,	V <sub>O</sub> = 2 V	-54		-126		
ЮН	High-level output current	Y outputs	V <sub>CC</sub> = 3.3 V,	V <sub>O</sub> = 2.6 V		-60		mA	
			V <sub>CC</sub> = 3.465 V,	V <sub>O</sub> = 3.135 V	-21		-46		
			V <sub>CC</sub> = 3.135 V,	$V_{O} = 1 V$	49		118		
IOL	Low-level output current	Y outputs	V <sub>CC</sub> = 3.3 V,	V <sub>O</sub> = 0.7 V		58		mA	
			V <sub>CC</sub> = 3.465 V,	V <sub>O</sub> = 0.4 V	23		53		
		А		VI = VCC			5		
Ιн	High-level input current	OE	V <sub>CC</sub> = 3.465 V,				20	μΑ	
		SCLOCK, SDATA					20		
		А					-5		
۱L	Low-level input current	OE	V <sub>CC</sub> = 3.465 V,	V <sub>I</sub> = GND	-10		-50	μA	
		SCLOCK, SDATA			-10		-50		
IOZ	High-impedance-state output	current	V <sub>CC</sub> = 3.465 V,	V <sub>O</sub> = 3.465 V or 0			±10	μA	
loff	Off-state current	SCLOCK, SDATA	$V_{CC} = 0 V,$	$V_I = 0 V$ to 5.5 V			50	μA	
ICC	Supply current		V <sub>CC</sub> = 3.465 V,	I <sup>O</sup> = 0		0.2	0.5	mA	
∆ICC	Change in supply current		$V_{CC} = 3.135$ V to 3.46 One input at $V_{CC} = 0$ . All other inputs at $V_{CC}$	6 V,			500	μA	
Ci	Input capacitiance		$V_{I} = V_{CC} \text{ or } GND,$	V <sub>CC</sub> = 3.3 V		4		pF	
Co	Output capacitance		$V_{O} = V_{CC} \text{ or } GND,$	V <sub>CC</sub> = 3.3 V		6		pF	
CI/O	SDATA I/O capacitance		$V_{I/O} = V_{CC}$ or GND,	VCC = 3.3 V		7		pF	



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### switching characteristics over recommended operating conditions

	PARAMETER		FROM	то	TEST CONDITIONS	MIN	MAX	UNIT
			А	Y		1.2	3.6	ns
<sup>t</sup> PLH	Low-to-high level propagation	SCLOCK↓	SDATA valid	$V_{CC}$ = 3.3 V ±0.185 V, See Figure 3		2	μs	
<sup>t</sup> PLH	Low-to-high level propagation	delay time	SDATA↑	Y	V <sub>CC</sub> = 3.3 V ±0.185 V, See Figure 3		150	ns
			А	Y		1.2	3.6	ns
<sup>t</sup> PHL	High-to-low level propagation	SCLOCK↓	SDATA valid	V <sub>CC</sub> = 3.3 V ±0.185 V, See Figure 3		2	μs	
<sup>t</sup> PHL	High-to-low level propagation	SDATA↑	Y	$V_{CC}$ = 3.3 V ±0.185 V, See Figure 3		150	ns	
<sup>t</sup> PZH	Enable time to the high level Enable time to the low level Disable time from the high level							
<sup>t</sup> PZL			OE	Y		1	4.7	
<sup>t</sup> PHZ			0E	r			4.7	ns
<sup>t</sup> PLZ	Disable time from the low leve							
<sup>t</sup> sk(o)	Skew time	А	Y			250	ps	
<sup>t</sup> sk(p)	Skew time		А	Y			500	ps
<sup>t</sup> sk(pr)	Skew time		А	Y			1	ns
tr	Rise time			Y		0.5	1.3	ns
	Rise time (see Note 4 and	SDATA			C <sub>L</sub> = 10 pF	6		
t <sub>r</sub>	Figure 3)	SDATA			C <sub>L</sub> = 400 pF		250	ns
t <sub>f</sub>	Fall time			Y		0.5	1.3	ns
4.	Fall time (see Note 4 and	CDATA			C <sub>L</sub> = 10 pF	20		
tf	Figure 3)	SDATA			C <sub>L</sub> = 400 pF		250	ns
					C <sub>L</sub> = 30 pF, T <sub>A</sub> = 70°C		100	
f	Operating frequency (see Note	Operating frequency (see Note 5)			$C_L = 20 \text{ pF}, T_A = 70^{\circ}\text{C}$		125	MHz
				C <sub>L</sub> = 15 pF, T <sub>A</sub> = 70°C		140		

NOTES: 4. This parameter has a lower limit than BUS specification. This allows use of series resistors for current spike protection.

5. See Figure 4 (Frequency versus Capacitive Load).



6 V 0 **S1** TEST **S**1 **500** Ω O Open From Output tPLH/tPHL Open **Under Test** GND tPLZ/tPZL 6 V  $C_L = 30 \text{ pF}$ tPHZ/tPZH GND **500** Ω (see Note A) tw LOAD CIRCUIT FOR tpd AND tsk 3 V Input 1.5 1.5 V From Output 0 V Under Test **VOLTAGE WAVEFORMS** C<sub>L</sub> = 30 pF (see Note A) Output Vcc Enable LOAD CIRCUIT FOR tr AND tf 1.5 V ν (high-level enabling) 0 V **t**PZL 3 V Input 1.5 V 1.5 V ≈ 3 V 0 V Output Waveform 1 1.5 <sup>t</sup>PLH V<sub>OL</sub> + 0.3 V <sup>t</sup>PHL S1 at 6 V Vol (see Note B) tPHZ VOH 2.4 2.4 V <sup>t</sup>PZH -Output 1.5 Output 0.4 V 4 V ۷он VOL Waveform 2 V<sub>OH</sub> – 0.3 V S1 at GND 1.5 V (see Note B) ≈ 0 V **VOLTAGE WAVEFORMS VOLTAGE WAVEFORMS** 

#### PARAMETER MEASUREMENT INFORMATION

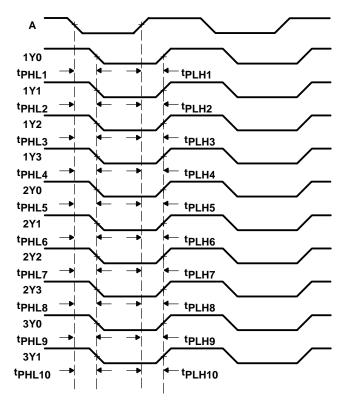
- NOTES: A. C<sub>L</sub> includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics: PRR  $\le$  10 MHz, Z<sub>Q</sub> = 50  $\Omega$ , t<sub>f</sub>  $\le$  2.5 ns. t<sub>f</sub>  $\le$  2.5 ns.
  - D. The outputs are measured one at a time with one transition per measurement.

#### Figure 1. Load Circuit and Voltage Waveforms



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#### PARAMETER MEASUREMENT INFORMATION



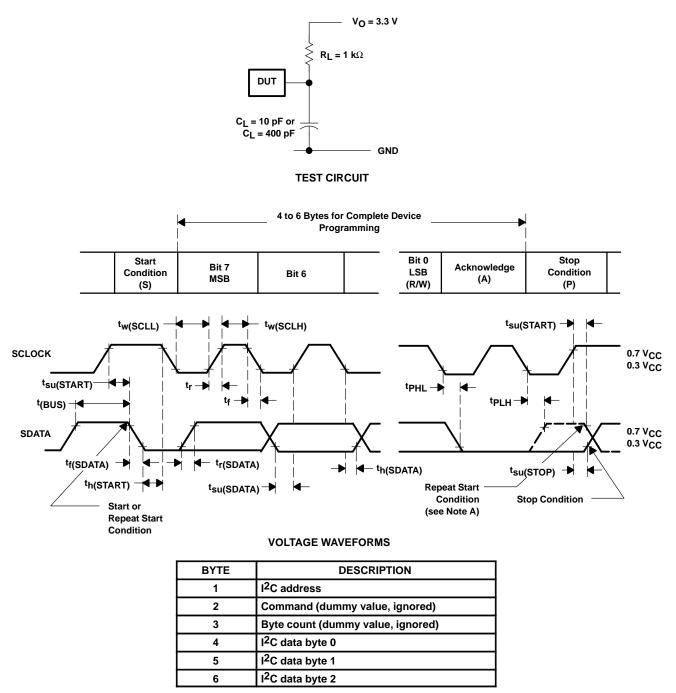
NOTES: A. Output skew,  $t_{Sk(0)}$ , is calculated as the greater of: - The difference between the fastest and slowest of  $t_{PLHn}$  (n = 1:10)

- The difference between the fastest and slowest of  $t_{PHLn}$  (n = 1:10)
- B. Pulse skew,  $t_{sk(p)}$ , is calculated as the greater of  $|t_{PLHn} t_{PHLn}|$  (n = 1:10).
- C. Process skew, tsk(pr), is calculated as the greater of:
  - The difference between the fastest and slowest of tPLHn (n = 1:10) across multiple devices under identical operating conditions
  - The difference between the fastest and slowest of tPHLn (n = 1:10) across multiple devices under identical operating conditions

Figure 2. Waveforms for Calculation of tsk(o), tsk(p), tsk(pr)



#### PARAMETER MEASUREMENT INFORMATION



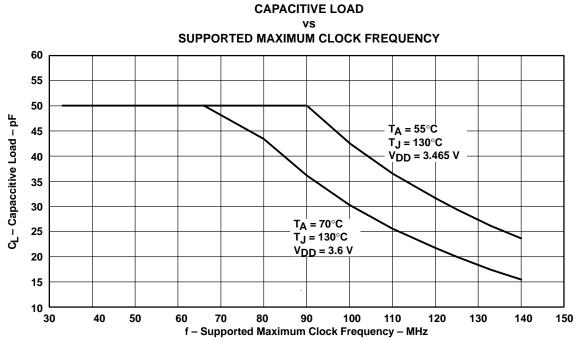
NOTES: A. The repeat start condition is not supported.

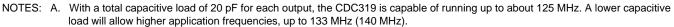
B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  100 kHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\geq$  10 ns, t<sub>f</sub>  $\geq$  10 ns.

Figure 3. Propagation Delay Times, tr and tf



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B. CPD for the CDC319 is about 25 pF per output (21 pF if C<sub>L</sub> < 20 pF) P(total) = VDD<sup>2</sup> × CPD × F<sub>O</sub> × N + (V<sub>OH</sub> - V<sub>OL</sub>)<sup>2</sup> × C<sub>L</sub> × F<sub>O</sub> × N + DC load where: N = number of switching outputs F<sub>O</sub> = clock frequency

Package thermal impedance (junction-to-ambient) =  $92.4^{\circ}$ C/W Maximum junction temperature =  $150^{\circ}$ C (< $125^{\circ}$ C recommended)

Figure 4





10-Dec-2020

## PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
CDC319DB	ACTIVE	SSOP	DB	28	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	CDC319	Samples
CDC319DBR	ACTIVE	SSOP	DB	28	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	CDC319	Samples
CDC319DBRG4	ACTIVE	SSOP	DB	28	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	CDC319	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

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<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# PACKAGE OPTION ADDENDUM

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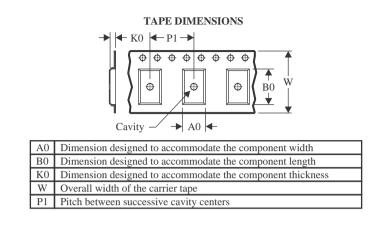


Texas

STRUMENTS

### TAPE AND REEL INFORMATION





#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal	

Device		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDC319DBR	SSOP	DB	28	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1



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# PACKAGE MATERIALS INFORMATION

3-Jun-2022



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDC319DBR	SSOP	DB	28	2000	356.0	356.0	35.0

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## TUBE



# - B - Alignment groove width

\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	Τ (μm)	B (mm)
CDC319DB	DB	SSOP	28	50	530	10.5	4000	4.1

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